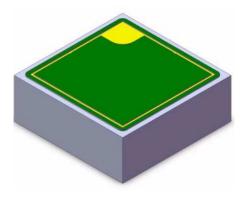
High Efficiency 20 mil ThinGaN LED (525 nm) Lead (Pb) Free Product - RoHS Compliant

ODT20RG



Features

- · High efficiency due to new ThinGaN concept
- Lambertian Emission pattern
- · Ideal for LCD backlighting and coupling in light guides
- Polarity: n-side up
- Wavelength (typ.): 525 nm
- · Technology: ThinGaN
- · Grouping parameters: luminous flux, wavelength

Applications

- · Outdoor displays
- Optical indicators
- Backlighting (LCD, switches, keys, displays, illuminated advertising, general lighting)
- Interior automotive lighting (e.g. dashboard backlighting, etc.)
- Marker lights (e.g. steps, exit ways, etc.)
- · Signal and symbol luminaire

Here you can find important REACH information of OSRAM Opto Semiconductors' products:

http://www.osram-os.com/osram_os/EN/Products/REACH

Please also note the special information in the section "Handling and storage conditions" on page 6.

Туре	Ordering Code	Description
ODT20RG-4953-X	Q65110A9436	20 mil high efficiency ThinGaN chip, 515- 545 nm, > 16 lm
•		

2009-08-01



Electrical values¹⁾ ($T_A = 25$ °C), correlated to OSRAM's Advanced Power TOPLED Plus Package

Parameter	Symbol	Value ²⁾			Unit
		min.	typ.	max.	
Dominant wavelength $I_F = 140 \text{ mA}, t_p = 30 \text{ms}$	λ_{dom}	515		545	nm
Reverse voltage $I_R = 10\mu A$	V_{R}	5			V
Forward voltage $I_F = 140 \text{ mA}, t_p = 30 \text{ ms}$	V _F	2.8		3.9	V
Luminous Flux $I_F = 140 \text{ mA}, t_p = 30 \text{ ms}$	Φ_{V}	16000			mlm

Measurement limits describe actual settings and do not include measurement uncertainties. Each wafer and fragment of a wafer is subject to final testing. The wafer or its pieces are individually attached on foils (rings). All el. values are referenced to the vendor's measurement system (correlation to customer product(s) is required). Measurement uncertainty +/-15% for brightness, +/- 1nm for wavelength and +/- 0.1V for voltage.



Due to the special conditions of the manufacturing processes of LED, the typical data or calculated correlations of technical parameters can only reflect statistical figures. These do not necessarily correspond to the actual parameters of each single product, which could differ from the typical data and calculated correlations or the typical characteristic line. If requested, e.g. because of technical improvements, these typ. data will be changed without any further notice.

Binning

Φ_{v} (mlm)	515 - 520 nm	520 - 535 nm	525 - 530 nm	530 - 535 nm	535 - 540 nm	540 - 545 nm
16000 - 20000	A49	B49	C49	D49	E49	F49
20000 - 25000	A50	B50	C50	D50	E50	F50
25000 - 32000	A51	B51	C51	D51	E51	F51
32000 - 40000	A52	B52	C52	D52	E52	F52
40000 - 50000	A53	B53	C53	D53	E53	F53

Maximum Ratings¹⁾

Parameter	Symbol	Value	Unit
Maximum operating temperature range	T_{op}	-40+100	°C
Maximum forward current (T _A = 25°C)	I_F	250	mA
Minimum forward current (T _A = 25°C)	I_F	30	mA
Maximum surge Current ($T_A = 25$ °C) $t_p = 10 \mu s$, D = 0.05	I_{peak}	0.5	A
Maximum junction temperature	T_{j}	125	°C



¹⁾ Maximum ratings are strongly package dependent and may differ between different packages. The values given represent the chip in an OSRAM Opto Semiconductor's Advanced Power TOPLED package.

Mechanical values1)

Symbol	Value ²⁾			Unit
	min.	typ.	max.	
L_x	0.45	0.50	0.55	mm
L_{y}	0.45	0.50	0.55	mm
D		100		mm
Н	170	190	210	μm
d	80	100	120	μm
	$egin{array}{c} L_x \ L_y \ D \ H \end{array}$	L_x 0.45 L_y 0.45 D 170	min. typ. L_x 0.45 0.50 L_y 0.45 0.50 D 100 H 170 190	min. typ. max. L_x 0.45 0.50 0.55 L_y 0.45 0.50 0.55 D 100 100 H 170 190 210

Additional information

Metallization frontside	Gold partial
Metallization backside	Gold
Die bonding	Epoxy bonding

All chips are checked according to the following procedure and the OSRAM OS specification of the visual inspection A63501-Q0002-N001-*-76G3:

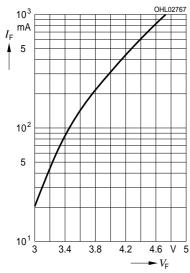
2009-08-01

Unless otherwise described below, the quality level of the final visual inspection shall comply to an AQL 0,4 (according MIL-STD-105E, level II), if the customer performes an incoming visual inspection of a shipment. The quality inspection (final visual inspection) is performed by production. An additional visual inspection step as special release procedure by QM after the final visual inspection is not installed.

Due to the special conditions of the manufacturing processes of LED, the typical data or calculated correlations of technical parameters can only reflect statistical figures. These do not necessarily correspond to the actual parameters of each single product, which could differ from the typical data and calculated correlations or the typical characteristic line. If requested, e.g. because of technical improvements, these typ. data will be changed without any further notice

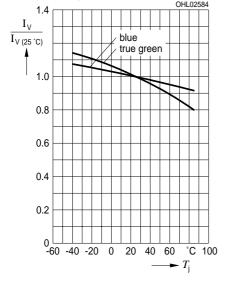
Forward current¹⁾

 $I_{\rm F} = f(V_{\rm F}), T_{\rm A} = 25 \, {\rm ^{\circ}C}$



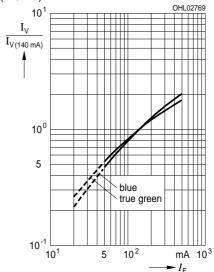
Relative luminous intensity¹⁾

 $I_{\text{V}}/I_{\text{V(25 °C)}} = f(T_{\text{j}})$; $I_{\text{F}} = 140$ mA, curve "true green"



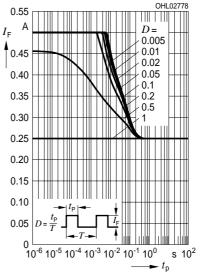
Relative luminous intensity^{1) 2)}

 $I_V/I_{V(140 \text{ mA})} = f(I_F)$, $T_A = 25 \text{ °C}$, curve "true green"



Permissible pulse handling capability¹⁾

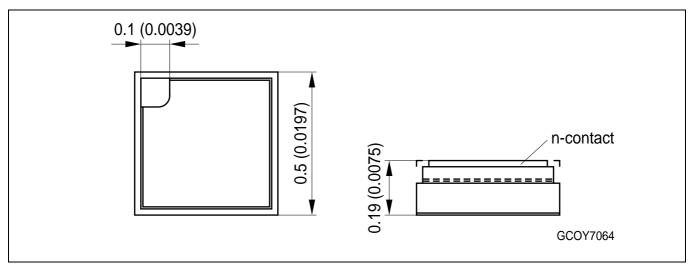
Duty cycle D = parameter, T_A = 25 °C



¹⁾ Due to the special conditions of the manufacturing processes of LED, the typical data or calculated correlations of technical parameters can only reflect statistical figures. These do not necessarily correspond to the actual parameters of each single product, which could differ from the typical data and calculated correlations or the typical characteristic line. If requested, e.g. because of technical improvements, these typ. data will be changed without any further notice. Given values are package dependent. The values represent the chip in an OSRAM Opto Semiconductor's Advanced Power TOPLED package.

²⁾In the range where the line of the graph is broken, you must expect higher brightness differences between single LEDs within one packing unit.

Chip Outlines



Dimensions are specified as typical¹⁾ values as follows: mm (inch).

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Attention please!

The information generally describes the type of component and shall not be considered as assured characteristics or detailed specification.

Terms of delivery and rights to change design reserved. Due to technical requirements components may contain dangerous substances. For information on the types in question please contact our sales organization.

Handling and Storage Conditions:

Storage time for wafers in sealed condition shall not exceed 6 months (storage ambient conditions: Ta=15...30°C; relative humidity: < 60%). The hermetically sealed shipment lot shall be opened under temperature and moisture controlled cleanroom environment only. Customer has to follow the according rules for disposition of material that can be hazardous for humans and environment.

Chips are placed on a blue foil, which may contain the following substance in a concentration of circ.18% wt: Bis (2-ethyl(hexyl)phthalate) (DEHP) [CAS #: 117-81-7; EC # 204-211-0]. Dice have to be handled ESD sensitive.

Packing

Chips are placed on a blue foil with minimum size of 18 x 18 cm² or alternatively on a blue foil inside a 6" ring. For shipment the wafers of a shipment lot are arranged to stacks. The stack is put in a plastic ESD bag with a maximum of 14 wafers in one bag. A maximum of 4 bags is put in a packaging box. A maximum of 5 packaging boxes is put in a shipping carton which is sealed for storage and shipment.

Please use the recycling operators known to you. We can also help you – get in touch with your nearest sales office. By agreement we will take packing material back, if it is sorted. You will have to bear the costs of transport. For packing material that is returned to us unsorted or which we are not obliged to accept, we shall have to invoice you for any costs incurred.

Label and shipping documents

Each wafer is identified with a sticker, which is attached to each wafer. The label shows chip type, wafer number, quantity, binning and the minimum, average and maximum values of voltage, luminous intensity and wavelength. Each wafer shipment includes an additional document, which summarizes the content.

Design objectives

a) workability

The chip design was developed and released based on the vendor's standard assembly procedures and packaging.



Bond strength properties are in accordance to MIL-STD-750D, method 2037. Whether the chip fits to the customer's product(c) with its according die and wire bond procedures and packaging must be evaluated by the customer himself. If workability problems arise after this release a mutually conducted problem solving procedure has to be set up, if the chips are suspected of contributing to the problems

b) chip characteristics

The chips are produced by the vendor with best effort, but on chip level a subset of the chip characteristics can be determined only. Performance of the chip in the customer's product(s) can only be determined by the customer himself.

Returns/Complaints

To return material because of technical or logistical reasons a RMA-number is necessary. Samples for analysis purposes can be send to OSRAM OS without credit.

Shipping Conditions:

If not otherwise arranged, the "General Conditions for the supply of products and services of the electrical and electronics industry" apply for any shipment. If these documents are not familiar to you, please request them at our nearest sales office.

Components used in life-support devices or systems must be expressly authorized by us for such purpose! Critical components²⁾, may only be used in life-support devices or systems³⁾ with the express written approval of OSRAM OS.

Revision History: 2009-08-01

Previous Version: n.a.

Page	Subjects (major change since last revision)	Date of change	

¹⁾ Typical (refered to as typ.) data are defined as long-term production mean values and are only given for information. This is not a specified value.

EU RoHS and China RoHS compliant product



此产品符合欧盟 RoHS 指令的要求; 按照中国的相关法规和标准,不含有毒有害物质或元素。

2009-08-01



²⁾A critical component is a component used in a life-support device or system whose failure can reasonably be expected to cause the failure of that life-support device or system, or to affect its safety or effectiveness of that device or system.

³⁾Life support devices or systems are intended (a) to be implanted in the human body, or (b) to support and/or maintain and sustain human life. If they fail, it is reasonable to assume that the health of the user may be endangered.